

SCAS801B-JUNE 2005-REVISED JULY 2007

#### **FEATURES**

- 1.8-V Phase Lock Loop Clock Driver for Double Data Rate (DDR II) Applications
- Spread Spectrum Clock Compatible
- Operating Frequency: 10 MHz to 340 MHz
- Low Current Consumption: <115 mA
- Low Jitter (Cycle-Cycle): ±30 ps
- Low Output Skew: 25 psLow Period Jitter: ±20 ps

- Low Dynamic Phase Offset: ±15 ps
- Low Static Phase Offset: ±50 ps
- Distributes One Differential Clock Input to Ten Differential Outputs
- 52-Ball µBGA (MicroStar<sup>™</sup> Junior BGA, 0,65-mm pitch)
- External Feedback Pins (FBIN, FBIN) are Used to Synchronize the Outputs to the Input Clocks
- Fail-Safe Inputs

#### **DESCRIPTION**

The CDCU877B is a high-performance, low-jitter, low-skew, zero-delay buffer that distributes a differential clock input pair (CK,  $\overline{CK}$ ) to ten differential pairs of clock outputs (Yn,  $\overline{Yn}$ ) and to one differential pair of feedback clock outputs (FBOUT, FBOUT). The clock outputs are controlled by the input clocks (CK,  $\overline{CK}$ ), the feedback clocks (FBIN,  $\overline{FBIN}$ ), the LVCMOS control pins (OE, OS), and the analog power input (AV<sub>DD</sub>). When OE is low, the clock outputs, except FBOUT/ $\overline{FBOUT}$ , are disabled while the internal PLL continues to maintain its locked-in frequency. OS (output select) is a program pin that must be tied to GND or V<sub>DD</sub>. When OS is high, OE functions as previously described. When OS and OE are both low, OE has no affect on Y7/ $\overline{Y7}$ , they are free running. When AV<sub>DD</sub> is grounded, the PLL is turned off and bypassed for test purposes.

When both clock inputs (CK,  $\overline{\text{CK}}$ ) are logic low, the device enters in a low power mode. An input logic detection circuit on the differential inputs, independent from input buffers, detects the logic low level and performs in a low power state where all outputs, the feedback, and the PLL are off. When the clock inputs transition from being logic low to being differential signals, the PLL turns back on, the inputs and the outputs are enabled, and the PLL obtains phase lock between the feedback clock pair (FBIN, FBIN) and the clock input pair (CK,  $\overline{\text{CK}}$ ) within the specified stabilization time.

The CDCU877B is able to track spread spectrum clocking (SSC) for reduced EMI. This device operates from —40°C to 85°C.

#### ORDERING INFORMATION

	(4)
T <sub>A</sub>	52-BALL BGA <sup>(1)</sup>
-40°C to 70°C	CDCU877BZQL

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### MicroStar Junior (ZQL) Package (TOP VIEW) GND 70 Υ5 2 3 5 6 Y6 <u>Y1</u> GND GND С (NB) <del>77</del> <u>Y2</u> GND GND D Y7 Y2 $V_{\text{DDQ}}$ OS $V_{\rm DDQ}$ $V_{DDQ}$ NB NB Ε **FBIN** CK $\mathsf{V}_{\mathsf{DDQ}}$ $V_{\text{DDQ}}$ NB NB **FBIN** CK $V_{DDQ}$ OE G AGND V<sub>DDQ</sub> **FBOUT** $V_{\text{DDQ}}$ $V_{DDQ}$ $V_{DDQ}$ NB NB Н **FBOUT** AV<sub>DD</sub> GND GND Y8 Υ3 GND GND GND-GND-74 <del>7</del>3 7 γ9 Υ8

- A. NC = No Connection
- B. NB = No Ball



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#### **TERMINAL FUNCTIONS**

	TERMINAL		DEGODIDATION
NAME	NO.	I/O	DESCRIPTION
AGND	G1		Analog ground
$AV_{DD}$	H1		Analog power
CK	E1	I	Clock input with a (10 kΩ to 100 kΩ) pulldown resistor
CK	F1	I	Complementary clock input with a (10 k $\Omega$ to 100 k $\Omega$ ) pulldown resistor
FBIN	E6	I	Feedback clock input
FBIN	F6	I	Complementary feedback clock input
FBOUT	H6	0	Feedback clock output
FBOUT	G6	0	Complementary feedback clock output
OE	F5	I	Output enable (asynchronous)
OS	D5	I	Output select (tied to GND or V <sub>DD</sub> )
GND	B2, B3, B4, B5, C2, C5, H2, H5, J2, J3, J4, J5		Ground
V <sub>DDQ</sub>	D2, D3, D4, E2, E5, F2, G2, G3, G4, G5		Logic and output power
Y[0:9]	A2, A1, D1, J1, K3, A5, A6, D6, J6, K4	0	Clock outputs
Y[0:9]	A3, B1, C1, K1, K2, A4, B6, C6, K6, K5	0	Complementary clock outputs

#### **FUNCTION TABLE**

		INPUTS			OUTPUTS					
AVDD	OE	os	CK	CK	Υ	Y	FBOUT	FBOUT	PLL	
GND	Н	Х	L	Н	L	Н	L	Н	Bypassed/Off	
GND	Н	X	Н	L	Н	L	Н	L	Bypassed/Off	
GND	L	Н	L	Н	L <sub>Z</sub>	L <sub>Z</sub>	L	Н	Bypassed/Off	
GND	L	L	Н	L	L <sub>Z</sub> Y7 Active	L <sub>Z</sub> <del>Y7</del> Active	Н	L	Bypassed/Off	
1.8 V Nominal	L	Н	L	Н	L <sub>Z</sub>	L <sub>Z</sub>	L	Н	On	
1.8 V Nominal	L	L	Н	L	L <sub>Z</sub> Y7 Active	L <sub>Z</sub> <del>Y7</del> Active	Н	L	On	
1.8 V Nominal	Н	Х	L	Н	L	Н	L	Н	On	
1.8 V Nominal	Н	Х	Н	L	Н	L	Н	L	On	
1.8 V Nominal	Х	Х	L	L	L <sub>Z</sub>	L <sub>Z</sub>	L <sub>Z</sub>	L <sub>Z</sub>	Off	
Х	Х	Х	Н	Н	Reserved					

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#### 1.8-V PHASE LOCK LOOP CLOCK DRIVER



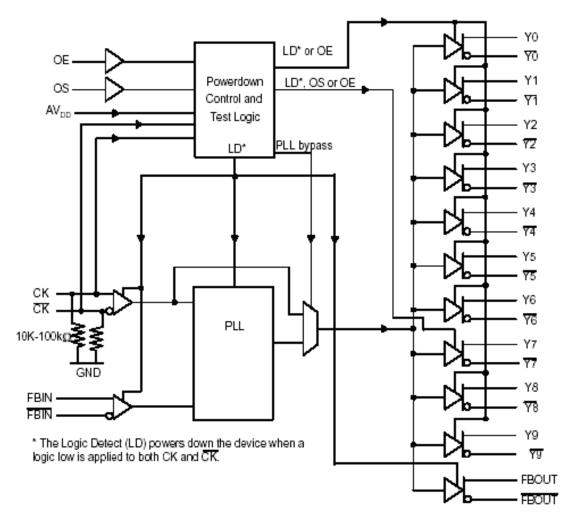


Figure 1. LOGIC DIAGRAM (POSITIVE LOGIC)



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#### **Absolute Maximum Ratings**(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range	V <sub>DDQ</sub> or AV <sub>DD</sub>	-0.5	2.5	V
VI	Input voltage range <sup>(2)(3)</sup>	V <sub>I</sub>	-0.5	2.5	V
Vo	Output voltage range (2)(3)	Vo	-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	$V_I < 0$ or $V_I > V_{DDQ}$		±50	mA
I <sub>OK</sub>	Output clamp current	$V_O < 0$ or $V_O > V_{DDQ}$		±50	mA
Io	Continuous output current	$V_O = 0$ to $V_{DDQ}$		±50	mA
	Continuous current through each V <sub>DDQ</sub> or	GND		±100	mA
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

(3) This value is limited to 2.5 V maximum.

#### **Recommended Operating Conditions**

			MIN	NOM	MAX	UNIT
V	Output supply voltage, V <sub>DDQ</sub>		1.7	1.8	1.9	V
$V_{CC}$	Supply Voltage, AV <sub>DD</sub>			$V_{DDQ}$		V
VI	Input voltage <sup>(1)</sup>				V <sub>CC</sub>	V
$V_{IL}$	Low-level input voltage (2)	OE, OS			0.35 x V <sub>DDQ</sub>	V
$V_{IH}$	High-level input voltage (2)	CK, CK	0.65 x V <sub>DDQ</sub>			V
I <sub>OH</sub>	High-level output current	·			-9	mA
I <sub>OL</sub>	Low-level output current (see Figu	ure 2)			9	mA
$V_{IX}$	Input differential-pair cross voltage	e (see Figure 2 )	(V <sub>DDQ</sub> /2) - 0.15		$(V_{DDQ}/2) + 0.15$	V
VI	Input voltage level		-0.3		V <sub>DDQ</sub> + 0.3	V
1/	Input differential voltage (2)	DC	0.3		V <sub>DDQ</sub> + 0.4	V
$V_{ID}$	(see Figure 9)	AC	0.63		V <sub>DDQ</sub> + 0.4	V
T <sub>A</sub>	Operating free-air temperature		-40		85	°C

<sup>(1)</sup> The PLL is turned off and bypassed for test purposes when AV<sub>DD</sub> is grounded. During this test mode, V<sub>DDQ</sub> remains within the recommended operating conditions and no timing parameters are specified.

<sup>(2)</sup> V<sub>ID</sub> is the magnitude of the difference between the input level on CK and the input level on CK, see Figure 9 for definition. The CK and CK, V<sub>IH</sub> and V<sub>IL</sub> limits define the dc low and high levels for the logic detect state.

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#### **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	$AV_{DD}$ , $V_{DDQ}$	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$V_{IK}$	Input		I <sub>I</sub> = 18 mA	1.7			-1.2	V
V	Lligh lovel output voltage		I <sub>OH</sub> = -100 μA	1.7 to 1.9	V <sub>DDQ</sub> - 0.2			V
V <sub>OH</sub>	High-level output voltage	*	$I_{OH} = -9 \text{ mA}$	1.7	1.1			V
V	Low-level output voltage		I <sub>OL</sub> = 100 μA				0.1	V
$V_{OL}$	Low-level output voltage		I <sub>OL</sub> = 9 mA	1.7			0.6	V
$I_{O(DL)}$	Low-level output current, dissabled		$V_{O(DL)} = 100 \text{ mV}, OE = L$	1.7	100			μΑ
$V_{OD}$	Differential output voltag	e <sup>(1)</sup>		1.7	0.5			V
		CK, CK		1.9			±250	
I	Input current	OE, OS, FBIN, FBIN		1.9			±10	μΑ
I <sub>DD(LD)</sub>	Supply current, static (I <sub>D</sub>	<sub>DQ</sub> + I <sub>ADD</sub> )	CK and $\overline{\text{CK}} = \text{L}$	1.9			500	μΑ
			CK and $\overline{\text{CK}}$ = 270 MHz. All outputs are open (not connected to a PCB)	1.9			115	
I <sub>DD</sub>	Supply current, dynamic (see Note <sup>(2)</sup> for CPD ca	(I <sub>DDQ</sub> + I <sub>ADD</sub> ) Iculation)	All outputs are loaded with 2 pF and 120-Ω termination resistor	1.9			215	mA
			All outputs are loaded with 10 pF and $120-\Omega$ termination resistor	1.9			235	
(	Input conscitones	CK, CK	V – V or CND	1.8	2		3	
C <sub>I</sub>	Input capacitance	FBIN, FBIN	$V_I = V_{DD}$ or GND	1.8	2		3	pF
	Change in input assessed	CK, CK	V – V or CND	1.8			0.25	þΓ
$C_{I(\Delta)}$	Change in input current	FBIN, FBIN	$V_I = V_{DD}$ or GND	1.8			0.25	

<sup>(1)</sup> V<sub>OD</sub> is the magnitude of the difference between the true and complimentary outputs. See Figure 9 for a definition.

#### Timing Requirements<sup>(1)</sup>

over recommended operating free-air temperature range (unless otherwise noted) (see )

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
4	Clock frequency (operating) <sup>(1)(2)</sup>		10	340	MHz
t <sub>CK</sub>	Clock frequency (application) <sup>(1)(3)</sup>	AV	160	340	MHz
t <sub>DC</sub>	Duty cycle, input clock	- AV <sub>DD</sub> , V <sub>DD</sub> = 1.8 V ±0.1 V	40%	60%	
tL	Stabiliztion time (4)			12	μs

<sup>(1)</sup> The PLL must be able to handle spread spectrum induced skew.

(3) Application clock frequency indicates a range over which the PLL must meet all timing parameters.

<sup>(2)</sup> Total I<sub>DD</sub> = I<sub>DDQ</sub> + I<sub>ADD</sub> = f<sub>CK</sub> × C<sub>PD</sub> × V<sub>DDQ</sub>, solving for C<sub>PD</sub> = (I<sub>DDQ</sub> + I<sub>ADD</sub>)/(f<sub>CK</sub> × V<sub>DDQ</sub>) where f<sub>CK</sub> is the input frequency, V<sub>DDQ</sub> is the power supply, and C<sub>PD</sub> is the power dissipation capacitance.

<sup>(2)</sup> Operating clock frequency indicates a range over which the PLL must be able to lock, but in which it is not required to meet the other timing parameters (used for low speed system debug).

<sup>(4)</sup> Stabilization time is the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power up. During normal operation, the stabilization time is also the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal when CK and CK go to a logic low state, enter the power-down mode and later return to active operation. CK and CK may be left floating after they have been driven low for one complete clock cycle.



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#### **Switching Characteristics**

over recommended operating free-air temperature range (unless otherwise noted) (see  $^{(1)}$ ) AV<sub>DD</sub>, V<sub>DD</sub> = 1.8 V  $\pm$  0.1 V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t <sub>en</sub>	Enable time, OE to any Y/Y	See Figure 11			8	ns	
t <sub>dis</sub>	Disable time, OE to any Y/Y	See Figure 11			8	ns	
		160 MHz to 200 MHz, see Figure 4	0		±40		
t <sub>jit(cc+)</sub>	Cycle-to-cycle period jitter <sup>(2)</sup>	200 MHz to 270 MHz, see Figure 4	0		±35	ps	
t <sub>jit(cc-)</sub>		270 MHz to 340 MHz, see Figure 4	0		±30		
t <sub>(ω)</sub>	Static phase offset time (3)	See Figure 5	-50		50	ps	
t <sub>(ω)dyn</sub>	Dynamic phase offset time	See Figure 10	-15		15	ps	
t <sub>sk(o)</sub>	Output clock skew	See Figure 6			25	ps	
	Period jitter (4)(2)	160 MHz to 200 MHz, see Figure 7	-30		30	ne	
t <sub>jit(per)</sub>		201 MHz to 340 MHz, see Figure 7	-20		20	ps	
		160 MHz to 190 MHz, see Figure 8		±90			
t <sub>jit(hper)</sub>	Half-period jitter (4)(2)	190 MHz to 250 MHz, see Figure 8		±60		ps	
		250 MHz to 340 MHz, see Figure 8		±40			
	Slew rate, OE	See Figure 9	0.5				
SR	Input clock slew rate	See Figure 9	1	2.5	4	V/ns	
	Output clock slew rate <sup>(5)(6)</sup> (no load)	See Figure 9 and Figure 13	1.5	2.5	3		
V <sub>OX</sub>	Output differential-pair cross voltage (7)	See Figure 2	(V <sub>DDQ</sub> /2) - 0.1		(V <sub>DDQ</sub> /2) + 0.1	V	
	SSC modulation frequency		30		33	kHz	
	SSC clock input frequency deviation		0%		-0.5%		
	PLL loop bandwidth		2			MHz	

<sup>(1)</sup> There are two different terminations that are used with the following tests. The load/board in Figure 2 is used to measure the input and output differential-pair cross voltage only. The load/board in Figure 3 is used to measure all other tests. For consistency, equal length cables must be used.

- (2) This parameter is specifieded by design and characterization.
- (3) Phase static offset time does not include jitter.
- (4) Period jitter, half-period jitter specifications are separate specifications that must be met independently of each other.
- 5) The output slew rate is determined from the IBIS model with a 120- $\Omega$  load only.
- (6) To eliminate the impact of input slew rates on static phase offset, the input skew rates of reference clock input CK and CK and feedback clock inputs FBIN and FBIN are recommended to be nearly equal. The 2.5-V/ns skew rates are shown as a recommended target. Compliance with these typical values is not mandatory if it can adequately shown that alternative characteristics meet the requirements of the registered DDR2 DIMM application.
- (7) Output differential-pair cross voltage specified at the DRAM clock input or the test load.



#### PARAMETER MEASUREMENT INFORMATION

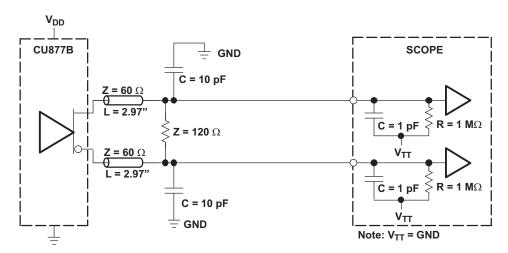


Figure 2. Output Load Test Circuit 1

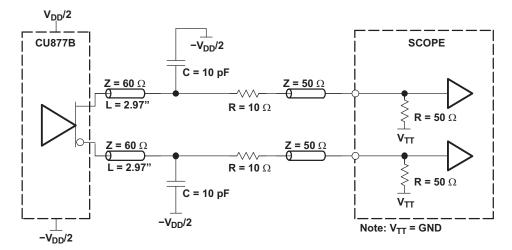


Figure 3. Output Load Test Circuit 2

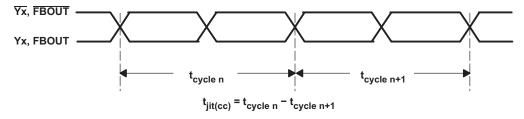


Figure 4. Cycle-To-Cycle Period Jitter

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# PARAMETER MEASUREMENT INFORMATION (continued)

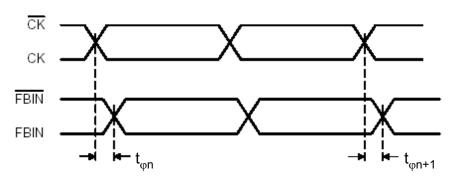


Figure 5. Static Phase Offset

$$t\phi = \frac{\sum_{1}^{n=N} t\phi n}{N}$$

(N is the large number of samples)

(N > 1000 samples)

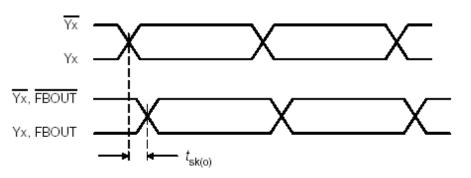


Figure 6. Output Skew

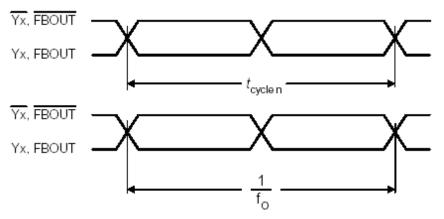


Figure 7. Period Jitter

$$t_{jit(per)} = t_{cycle n} - \frac{1}{f_O}$$

(f<sub>O</sub> average input frequency measured at  $CK/\overline{CK}$ 

(2)

(1)



(3)

## **PARAMETER MEASUREMENT INFORMATION (continued)**

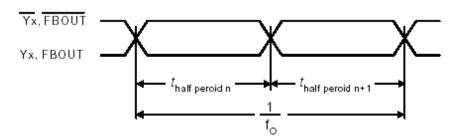


Figure 8. Half-Period Jitter

$$t_{jit(hper)} = t_{half period n} - \frac{1}{2 \times f_{O}}$$

n = any half cycle

(fo average input frequency measured at CK/CK

Clock Inputs and Outputs, OE  $t_{r(i)}, t_{r(o)}$ 

Figure 9. Input and Output Slew Rates

$$sIrr_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{r(i/o)}} \qquad sIrf_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{f(i/o)}}$$

$$CK$$

$$CK$$

$$FBIN$$

$$FBIN$$

$$t_{\phi dyn}$$

Figure 10. Dynamic Phase Offset



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#### PARAMETER MEASUREMENT INFORMATION (continued)

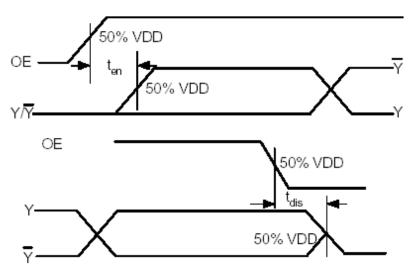
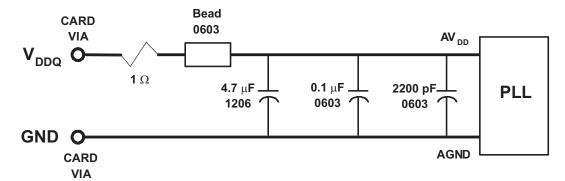


Figure 11. Time Delay Between OE and Clock Output  $(Y, \overline{Y})$ 

#### RECOMMENDED AV<sub>DD</sub> FILTERING



- Place the 2200-pF capacitor close to the PLL.
- Use a wide trace for the PLL analog power and ground. Connect PLL and capacitors to AGND trace and connect trace to one GND via (farthest from the PLL).
- C. Recommended bead: Fair-Rite PN 2506036017Y0 or equilvalent (0.8  $\Omega$  dc maximum, 600  $\Omega$  at 100 MHz).

Figure 12. Recommended AV<sub>DD</sub> Filtering

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## PARAMETER MEASUREMENT INFORMATION (continued)

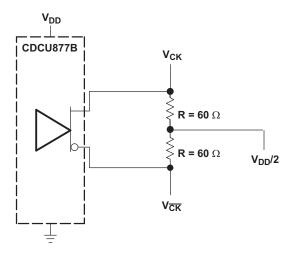


Figure 13.



#### PACKAGE OPTION ADDENDUM

3-Jul-2007

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
CDCU877BZQLR	ACTIVE	BGA MI CROSTA R JUNI OR	ZQL	52	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR
CDCU877BZQLT	ACTIVE	BGA MI CROSTA R JUNI OR	ZQL	52	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

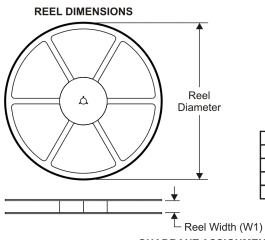
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

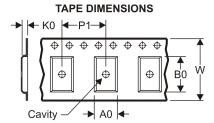
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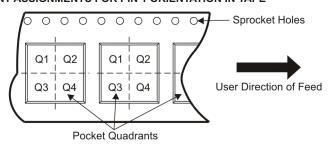
#### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

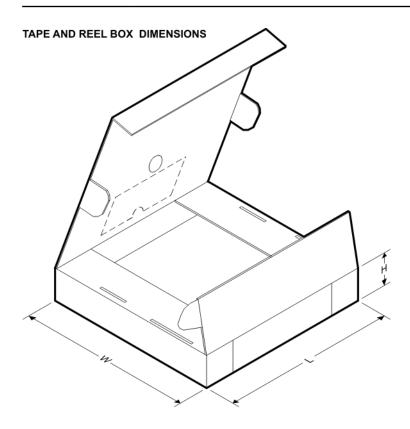
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



\*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCU877BZQLR	BGA MI CROSTA R JUNI OR	ZQL	52	1000	330.0	16.4	4.8	7.3	1.5	8.0	16.0	Q1
CDCU877BZQLT	BGA MI CROSTA R JUNI OR	ZQL	52	250	330.0	16.4	4.8	7.3	1.5	8.0	16.0	Q1



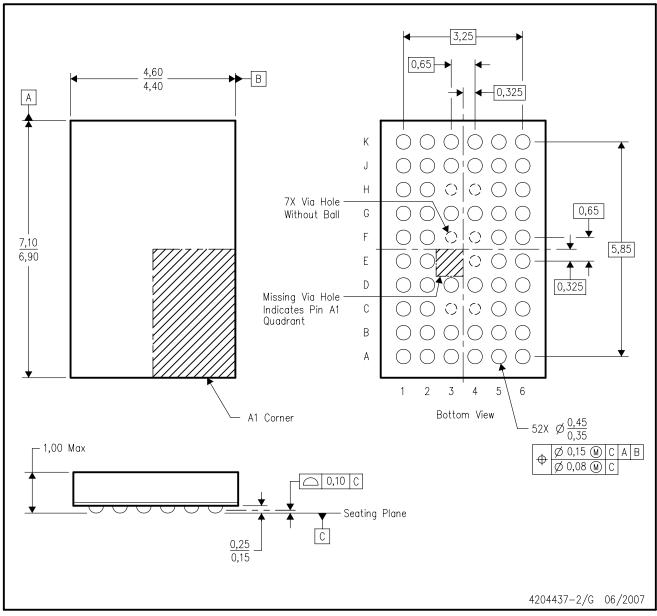


#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCU877BZQLR	BGA MICROSTAR JUNIOR	ZQL	52	1000	333.2	345.9	28.6
CDCU877BZQLT	BGA MICROSTAR JUNIOR	ZQL	52	250	333.2	345.9	28.6

# ZQL (R-PBGA-N52)

## PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is lead-free. Refer to the 52 GQL package (drawing 4200583) for tin-lead (SnPb).



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401 Building No.5, JiuGe Business Center, Lane 2301, Yishan Rd Minhang District, Shanghai , China

#### > Sales:

Direct +86 (21) 6401-6692

Email amall@ameya360.com

QQ 800077892

Skype ameyasales1 ameyasales2

#### Customer Service :

Email service@ameya360.com

# Partnership :

Tel +86 (21) 64016692-8333

Email mkt@ameya360.com